The Analysis Report USB-TAP cannot workable problem

Issue date: 2010/10/13 **Report date:** 2010/12/13

Problem description: There is a few USB-TAP cannot workable in COP RDB

Fail rate: < 1%

Effect boards: MPC8377E-RDB REV 2.1, MPC8315E-RDB REV A3

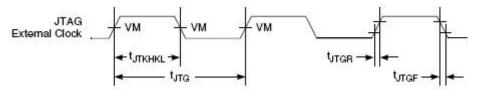
Root cause: It's a timing margin issue.

The EMI decoupling capacitor C118 (0.1uF) is too large to slowdown the falling time of TCK (JTAG signal). It makes the setup and hold time over

IEEE1149.1 specification.

Analysis:

1. The Timing Specification



VM = Midpoint Voltage (NVDD/2)

Figure JTAG Clock Input Timing Diagram

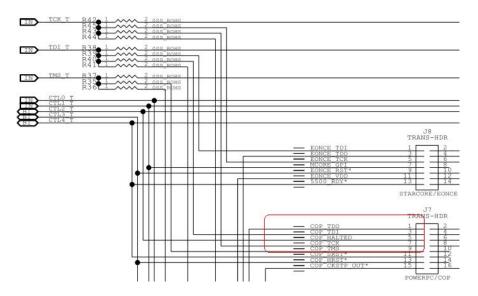
Parameter	Symbol ²	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f _{JTG}	0	33.3	MHz	_
JTAG external clock cycle time	t _{JTG}	30	_	ns	_
JTAG external clock pulse width measured at 1.4 V	[†] ЛТКНКL	15	_	ns	_
JTAG external clock rise and fall times	t _{JTGR} , t _{JTGF}	0	2	ns	_

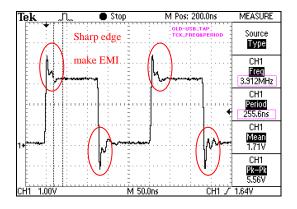
2. Original USB-TAP (Rev.C), no stuff 0.1uF in C118

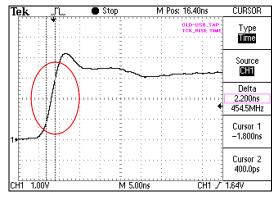
JTAG timing: t_{JTGR=2.2nS}, t_{JTGF=2.2nS} meet spec _{2ns} (note: probe Tek 116526 has lag)

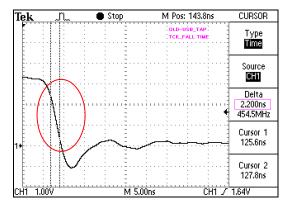
JTAG Functionality: PASS EMI in CE/FCC: FAIL











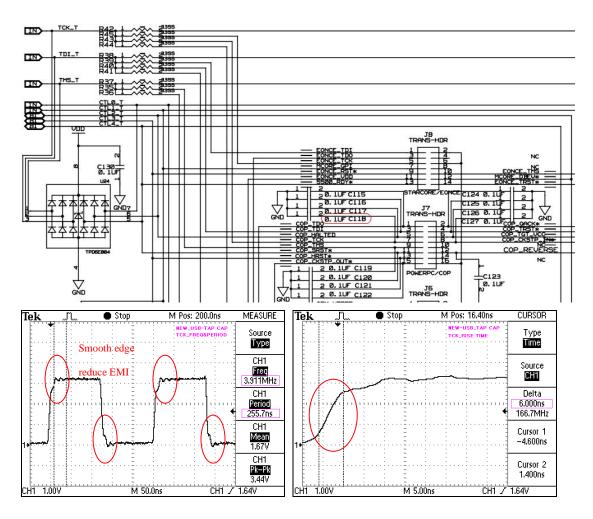
3. NEW USB-TAP (REV.D), C118 stuff 0.1uF

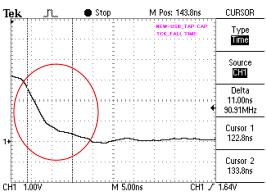
JTAG timing: t_{JTGR=6nS}, t_{JTGF=11nS} over spec _{2ns} (note: probe Tek 116526 has lag)

JTAG Functionality: Some models are fail

EMI in CE/FCC: PASS







4. Rework NEW USB-TAP (REV.D) by <u>stuff 47pF in C118</u> and <u>120OHM@100MHz</u> <u>bead in R43</u>, The pi filter reduce EMI and no effect signal timing.

JTAG timing: t_{JTGR=3.4nS}, t_{JTGF=4nS} over spec _{2ns} (note: probe Tek 116526 has lag)

JTAG Functionality: PASS EMI in CE/FCC: PASS

